



FQB16N25C/FQI16N25C 250V N-Channel MOSFET

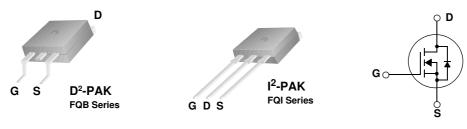
Features

- 15.6A, 250V, $R_{DS(on)} = 0.27 \Omega @V_{GS} = 10 V$
- Low gate charge (typical 41nC)
- Low Crss (typical 68pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability

Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supplies, DC-AC converters for uninterrupted power supplies and motor controls.



Absolute Maximum Ratings

Symbol	Parameter		FQB16N25C / FQI16N25C	Units	
$V_{\rm DSS}$	Drain-Source Voltag	je		250	V
I _D	Drain Current -	Continuous (T _C = 25°C)		15.6	Α
	-	Continuous (T _C = 100°C)		9.8	Α
I_{DM}	Drain Current -	Pulsed	(Note 1)	62.4	Α
V_{GSS}	Gate-Source Voltage	е		±30	V
E _{AS}	Single Pulsed Avala	nche Energy	(Note 2)	410	mJ
I_{AR}	Avalanche Current		(Note 1)	15.6	Α
E_AR	Repetitive Avalanch	e Energy	(Note 1)	13.9	mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	5.5	V/ns
P_{D}	Power Dissipation (Power Dissipation (T _A = 25°C)*		3.13	W
	Power Dissipation (Γ _C = 25°C)		139	W
		- Derate above 25°C		1.11	W/°C
T_J,T_STG	Operating and Stora	Operating and Storage Temperature Range		-55 to +150	°C
T_L	Maximum lead temperature for soldering purposes,				

Thermal Characteristics

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQB16N25C	FQB16N25CTM	D2-PAK	330mm	24mm	800
FQI16N25C	FQI16N25CTU	I2-PAK			50

Electrical Characteristics $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Charac	eteristics					1
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I_{D} = 250 μ A	250			V
$\Delta BV_{DSS}/$ ΔT_J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		0.31		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 250 V, V _{GS} = 0 V			10	μА
		V _{DS} = 200 V, T _C = 125°C			100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
On Charact	teristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 7.8A		0.22	0.27	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 7.8 A (Note 4)		10.5		S
Dynamic Cl	haracteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		830	1080	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		170	220	pF
C _{rss}	Reverse Transfer Capacitance			68	89	pF
Switching C	Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 125 V, I _D = 15.6A,		15	40	ns
t _r	Turn-On Rise Time	$R_G = 25 \Omega$		130	270	ns
t _{d(off)}	Turn-Off Delay Time			135	280	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		105	220	ns
Qg	Total Gate Charge	V _{DS} = 200 V, I _D = 15.6A,		41	53.5	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		5.6		nC
Q _{gd}	Gate-Drain Charge	(Note 4, 5)		22.7		nC
Drain-Source	ce Diode Characteristics and Maximum Ratings	3				
I _S Maximum Continuous Drain-Source Diode Forward Current					15.6	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				62.4	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 15.6 A			1.5	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 15.6 A,		260		ns
Q _{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		2.47		μС

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NOTES

- 1. Repetitive Rating : Pulse width limited by maximum junction temperature
- 2. L = 2.7mH, I $_{AS}$ = 15.6A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25°C
- 3. $I_{SD} \le$ 15.6A, di/dt \le 300A/ μ s, $V_{DD} \le$ BV $_{DSS}$, Starting T_J = 25°C
- 4. Pulse Test : Pulse width $\leq 300 \mu s, \ \text{Duty cycle} \leq 2\%$
- 5. Essentially independent of operating temperature

Typical Performance Characteristics

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics

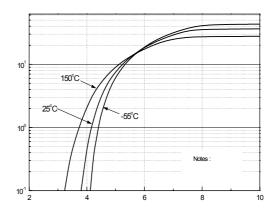


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperatue

Figure 5. Capacitance Characteristics

Figure 6. Gate Charge Characteristics

Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature

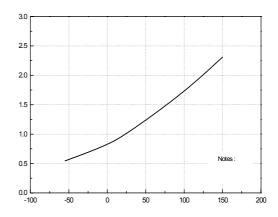
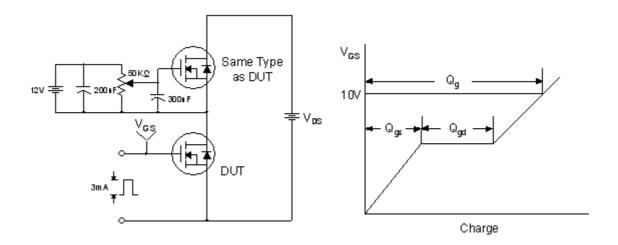


Figure 9. Maximum Safe Operating Area

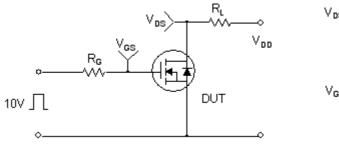
Figure 10. Maximum Drain Current vs. Case Temperature

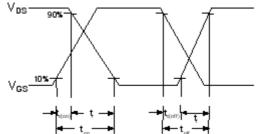
Figure 11. Transient Thermal Response Curve

Gate Charge Test Circuit & Waveform

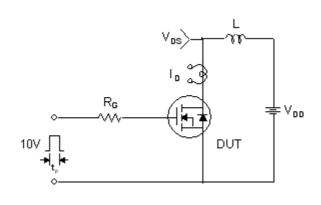


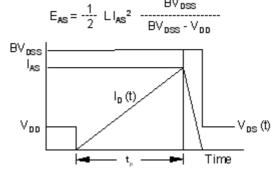
Resistive Switching Test Circuit & Waveforms



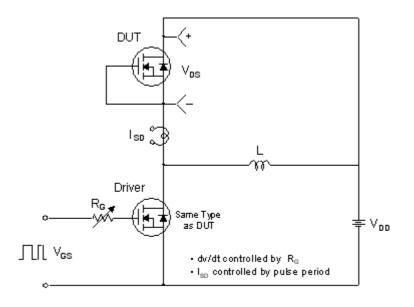


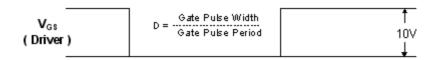
Unclamped Inductive Switching Test Circuit & Waveforms

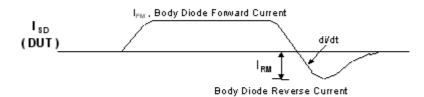


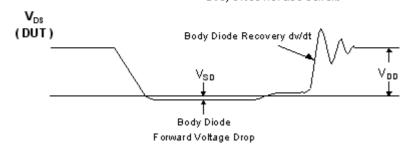


Peak Diode Recovery dv/dt Test Circuit & Waveforms





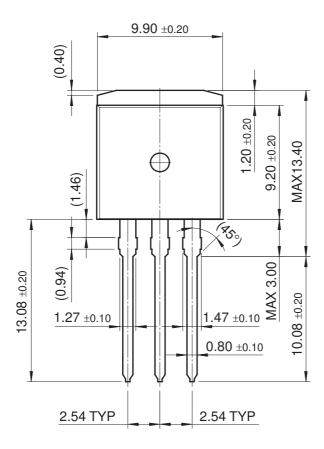


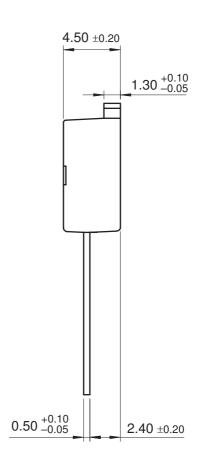


Mechanical Dimensions D²-PAK 4.50 ± 0.20 (0.40) 9.90 ± 0.20 1.30 +0.10 -0.05 1.20 ±0.20 9.20 ± 0.20 2.00 ± 0.10 5.30 ± 0.30 1.40 ± 0.20 0.10 ± 0.15 2.54 ±0.30 2.40 ±0.20 4.90 ± 0.20 (0.75) 1.27 ± 0.10 0.80 ±0.10 $0.50 \, ^{+0.10}_{-0.05}$ 2.54 TYP 2.54 TYP 10.00 ± 0.20 (8.00) (4.40)(1.75) 10.00 ± 0.20 (7.20)9.20 ±0.20 (2XR_{0.45}) 15.30 ±0.30 4.90 ±0.20 0.80 ±0.10 Dimensions in Millimeters

Package Dimensions (Continued)

I²-PAK







Dimensions in Millimeters

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